

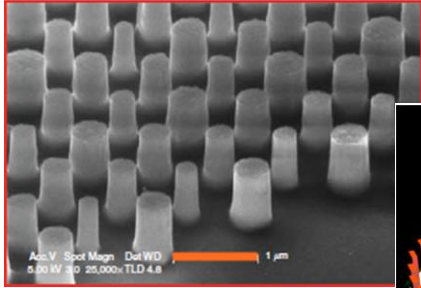
Hybrid meta-surface lens system for long wave infrared applications

Lieven Penninck, Sebastien Heron

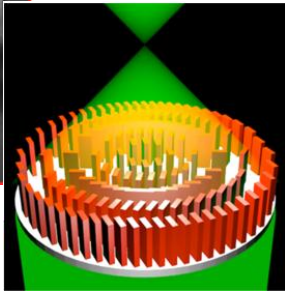


PlanOpSim
Enlightened Planar Optics

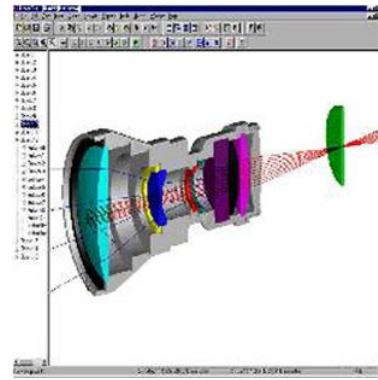
Nano-scale design



Component design



System Integration

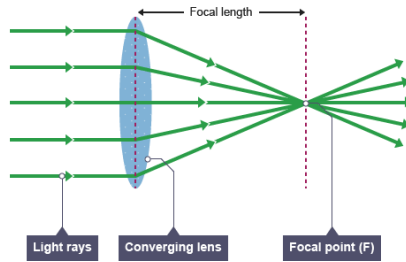


Planopsim's mission
Planopsim supplies R&D tools to engineers & scientists that allow to unlock the maximum benefit of flat optics in a user-friendly way.

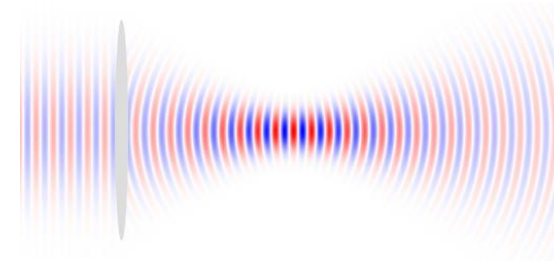
- ❖ Computer Aided Design software for Planar Optics & metasurfaces
 - All-in-one design workflow
- ❖ Design service for metasurfaces and photonics
 - In-house and 3^d party tools



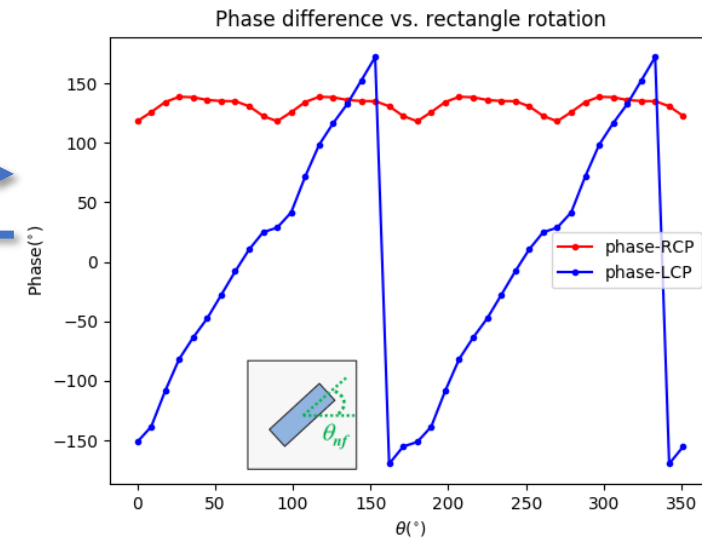
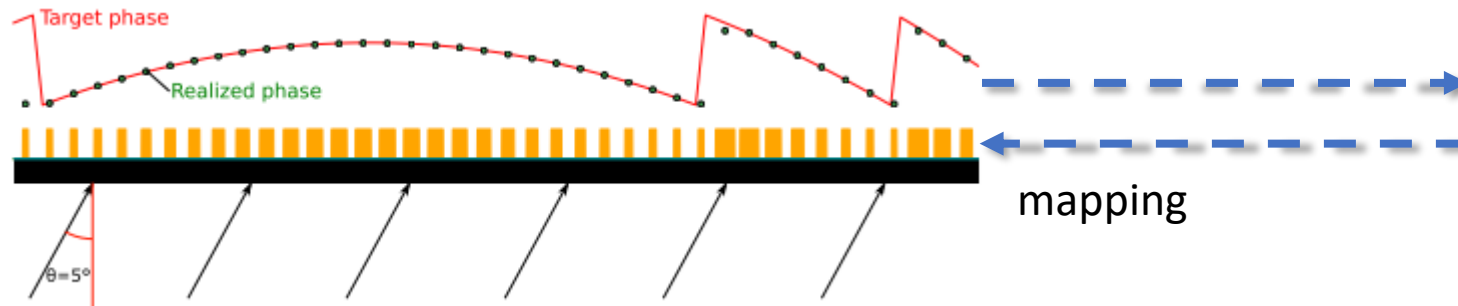
Ray picture



Wave picture



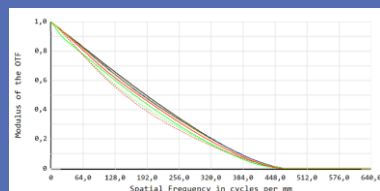
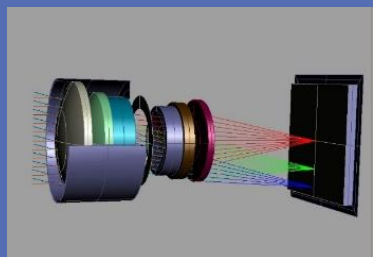
- ❖ Any component works by re-arranging the wavefront of the incoming waves
- ❖ Meta-atoms locally control exit phase and amplitude



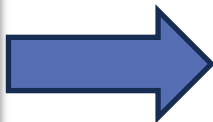
- ❖ Full control of wavefront
 - Any profile can be reproduced
 - Including difficult shapes: aspheric lenses, arrays
 - Functionalize: spectral, polarization, dispersion, multiplexing

System model

- Ray tracing
- Analytical

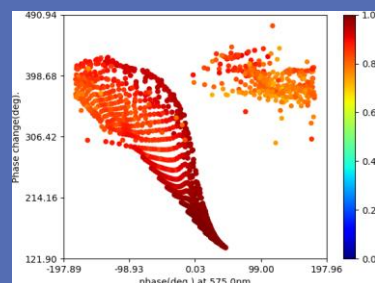
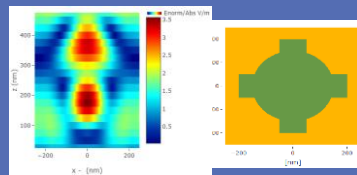


Ideal wavefront



Meta-atom design

- Full wave
- nm scale

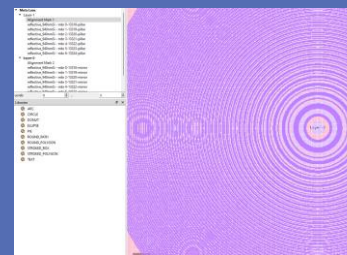
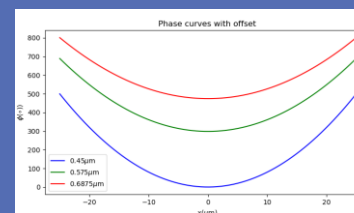


Meta-atoms



Component Design

- Target matching
- mm scale

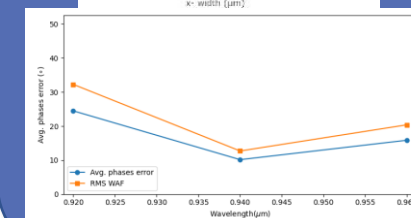
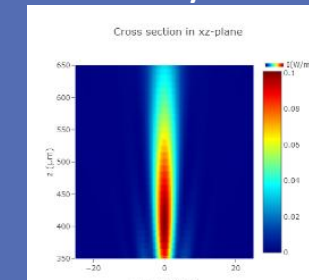


Wavefront



Analysis

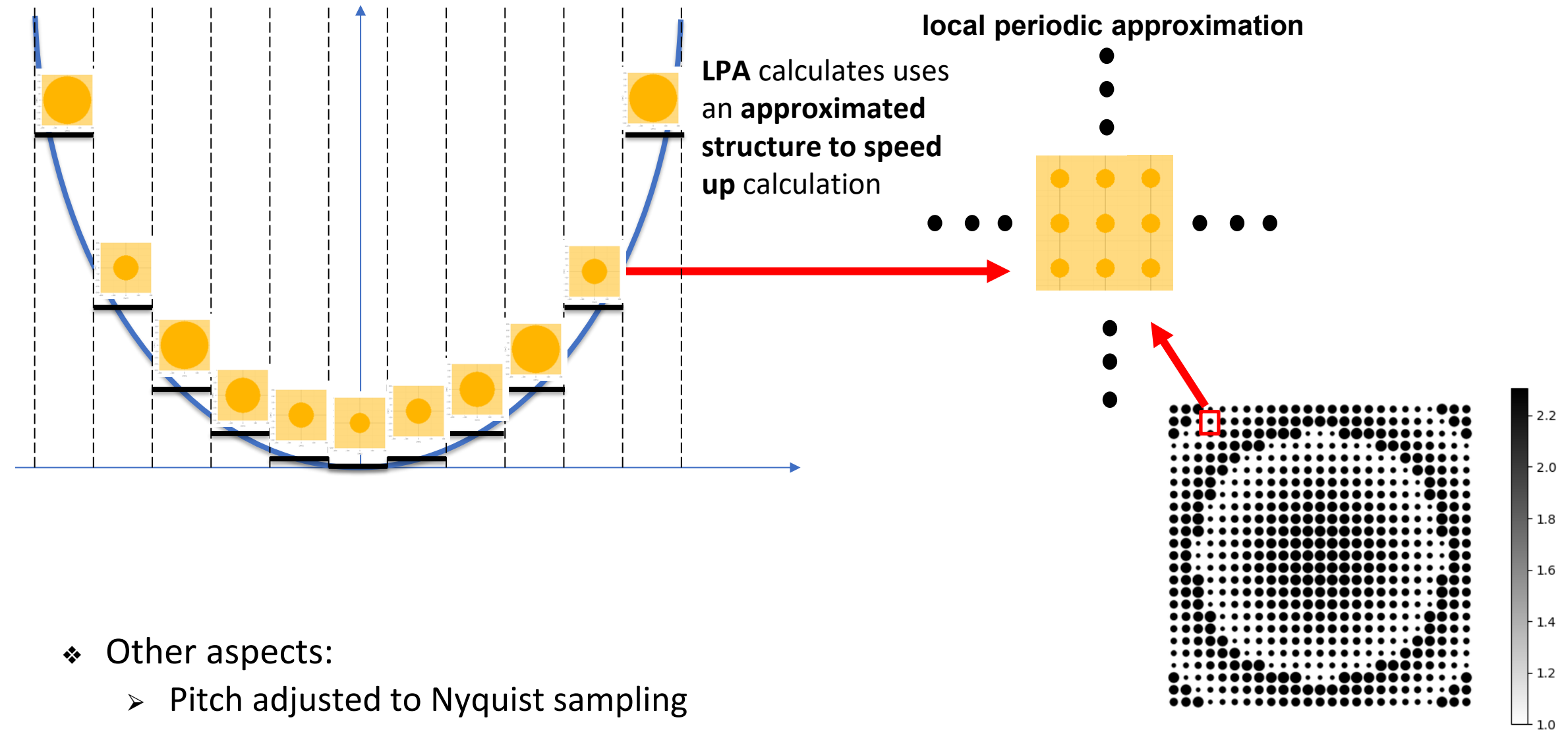
- Physical Optics
- Efficiency & PSF



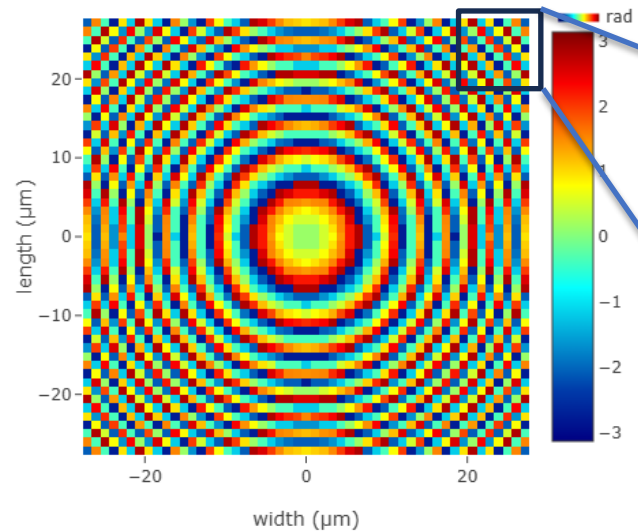
❖ Ray-tracing

❖ Full wave calculation
❖ Maxwell solver (RCWA)

❖ Propagation optics

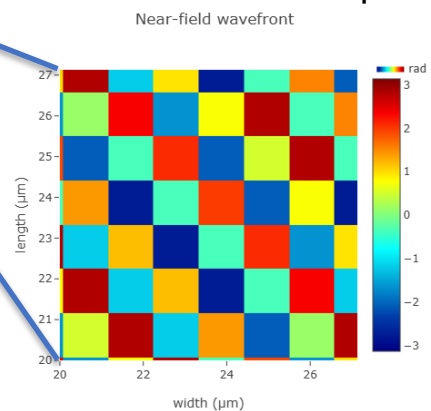


Near-field wavefront

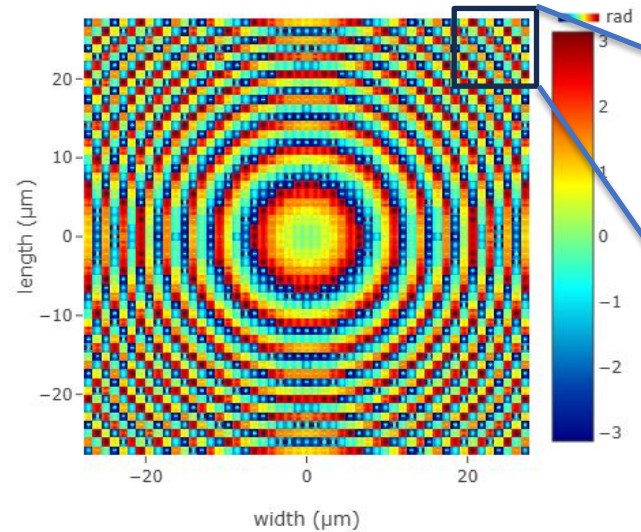


LPA

Phase profile

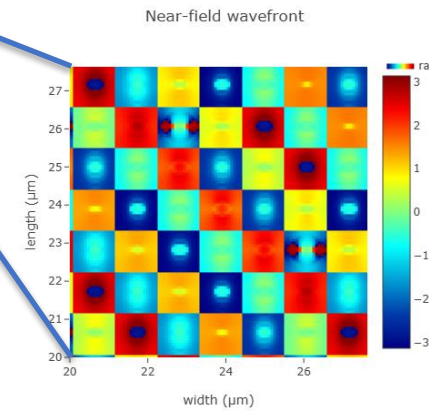


Near-field wavefront

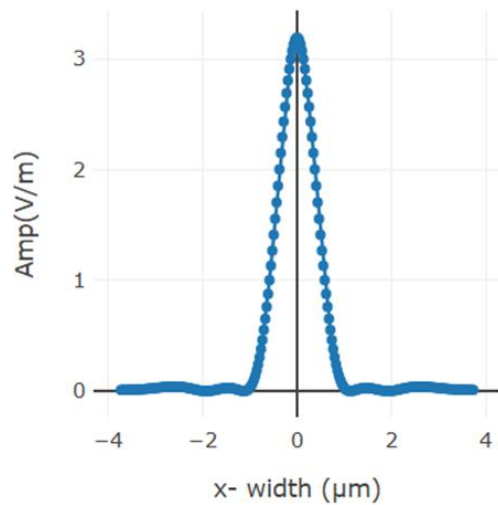


LFA

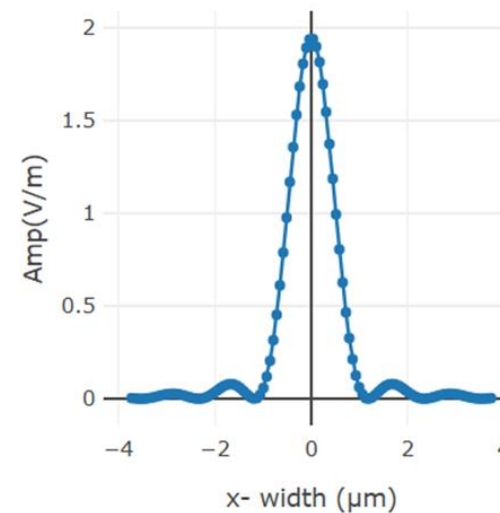
Phase profile



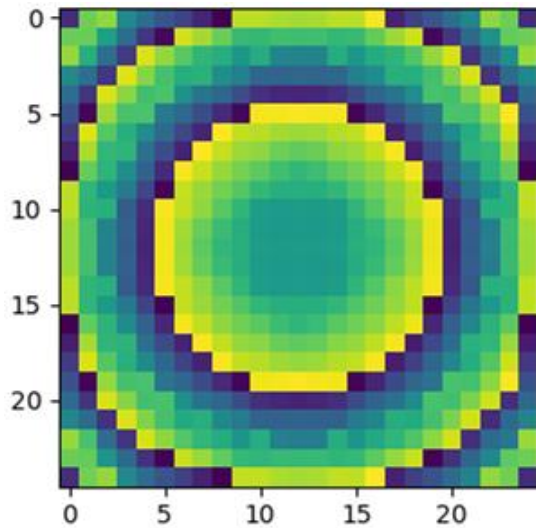
PSF section



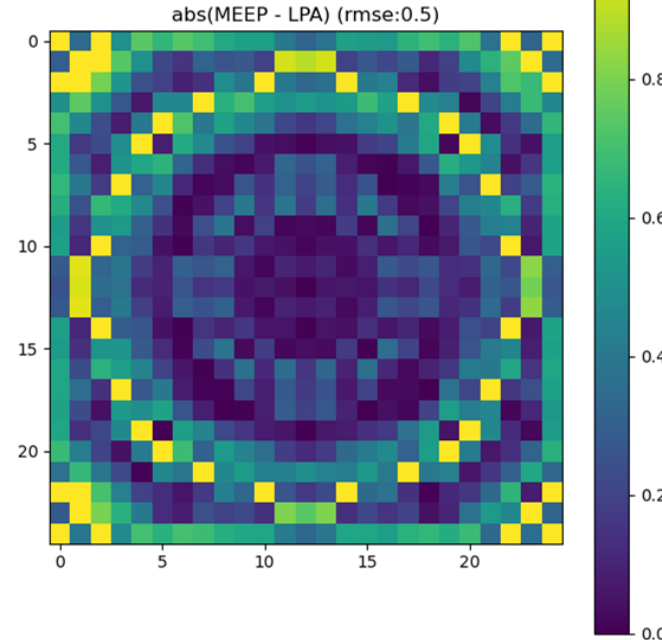
PSF section



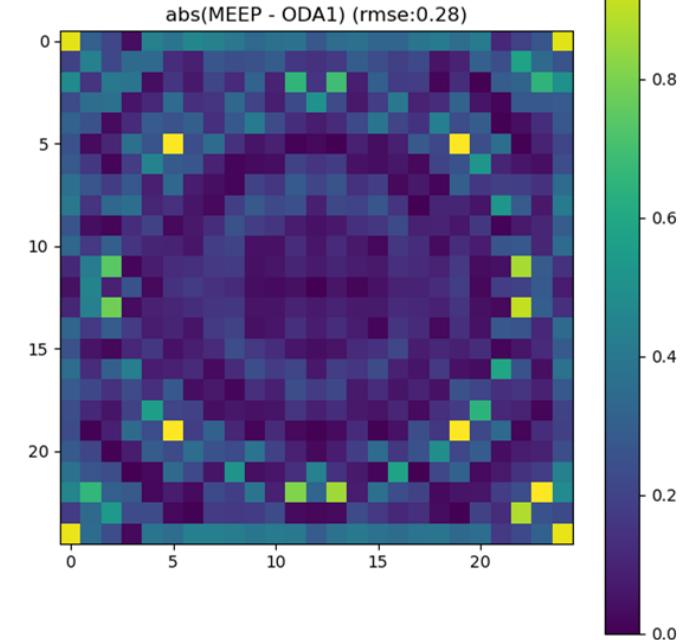
Full wave 'ground truth'



LPA error map



ODA error map



Overlapping Domain and Local Field Analysis improve meta-surface calculation accuracy and are faster than full wave calculation

	Calculation time*	Memory usage	Max. diameter
Standard LPA	1 minute	<1Gb	15000 μm
LFA	2 minutes	<1Gb	1363 μm
ODA	2.5 minutes	8Gb	120 μm **
Benchmark (meep)	6 hours	32Gb	10 μm

*10 μm diameter metalens
Core i9, 64Gb RAM PC
** Time limited to 24h calculation

- ❖ Specific challenges of LWIR range:
 - Few transparent materials
 - Weak signal → Large aperture needed
 - Availability of raw material
 - Expensive materials

- ❖ Wavelength range 8-12 μ m

- ❖ Additional constraint reduce nr. of lenses

Dispersion engineering

Dispersion corrected

Single wavelength design

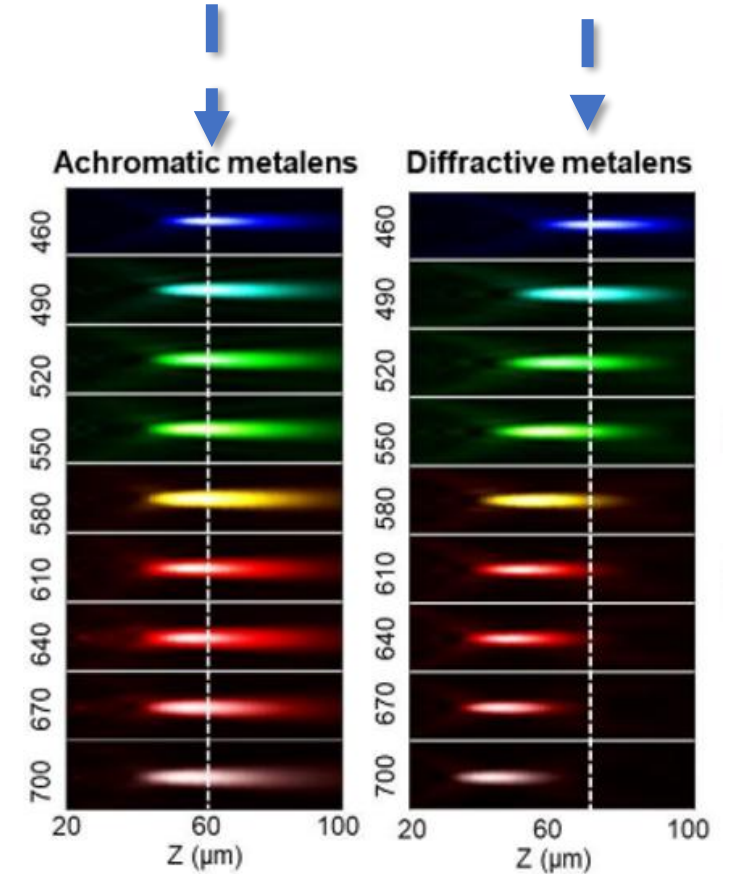
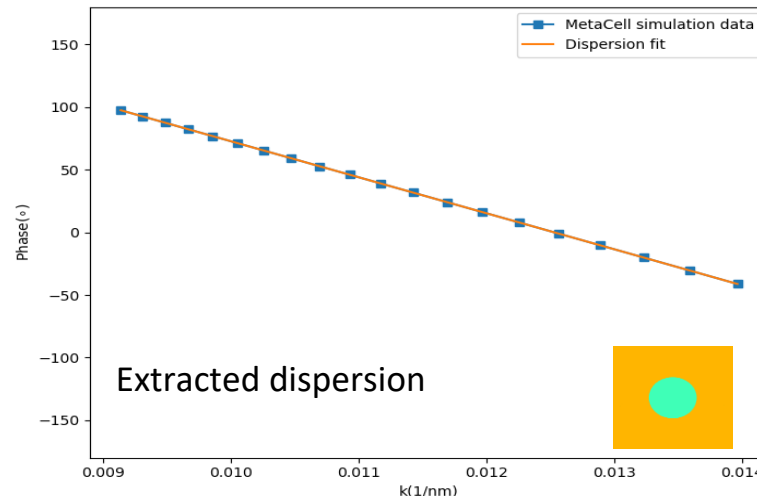
- ❖ Meta-surface offer control on material dispersion
- ❖ Dispersion engineering -> controlling phase and phase dispersion

Group delay (1st order)

$$\varphi(r, \lambda) = \varphi_c(r) + \frac{d\varphi(r)}{dk} \Delta k + \frac{d^2\varphi(r)}{d^2k} \Delta k^2 + \dots$$

Group delay dispersion (2nd order)

- ❖ Extract phase and slope per structure



Wang, S. *et al.* A broadband achromatic metalens in the visible. *Nat. Nanotechnol.* **13**, 227–232 (2018).

Limits of dispersion engineering

- ❖ Maximum dispersion in dielectric meta-atom

$$\Delta\Phi = 2\pi h \left(\frac{n_{core}}{\lambda_1} - \frac{n_{clad}}{\lambda_2} \right)$$

- ❖ Bandwidth, size and function are connected

$$\varphi(\lambda, r) = \frac{2\pi}{\lambda} \left(\sqrt{r^2 + f^2} - f \right)$$

$$R_{max} \leq \frac{\Delta\Phi \cdot c}{\Delta\omega \left(\frac{1}{NA} - \sqrt{\frac{1}{NA^2} - 1} \right)}$$

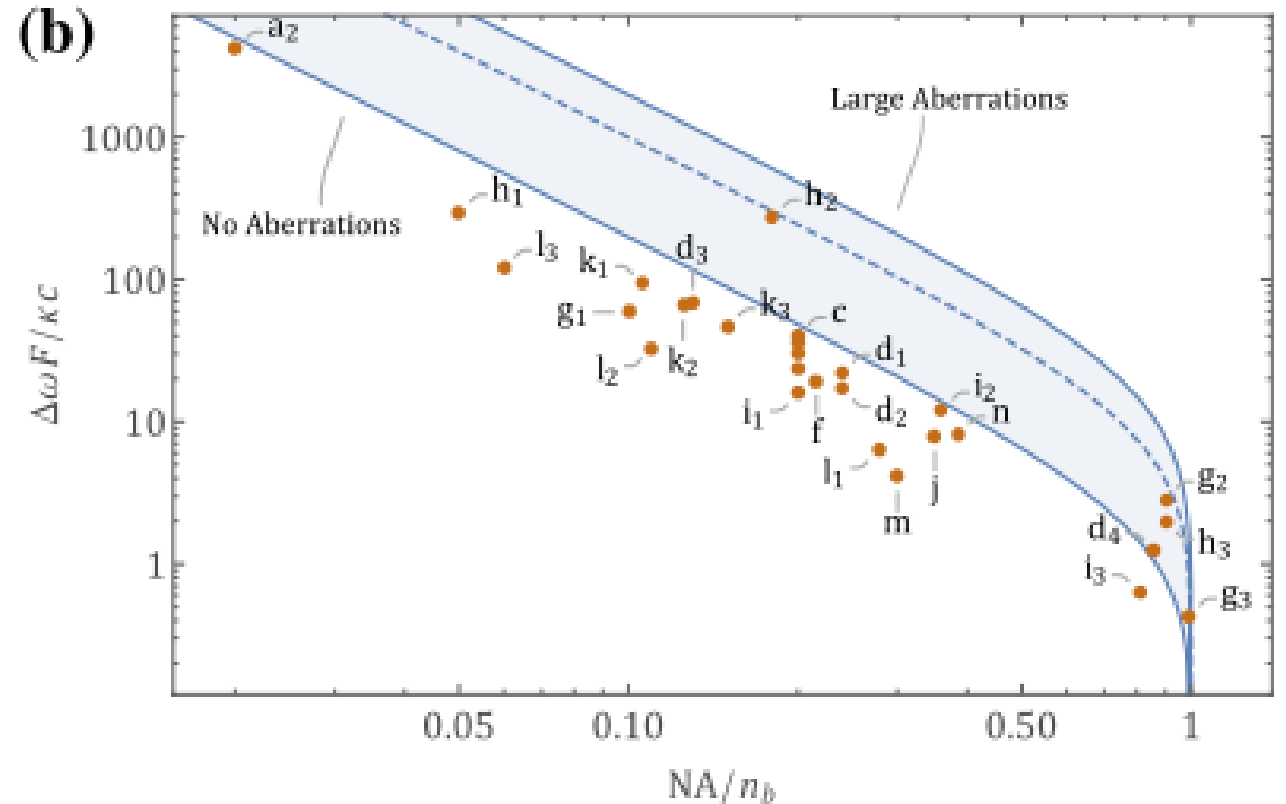
Application parameters

- Bandwidth
- Diameter
- Spatial frequency, NA

Design parameters: $\Delta\Phi$

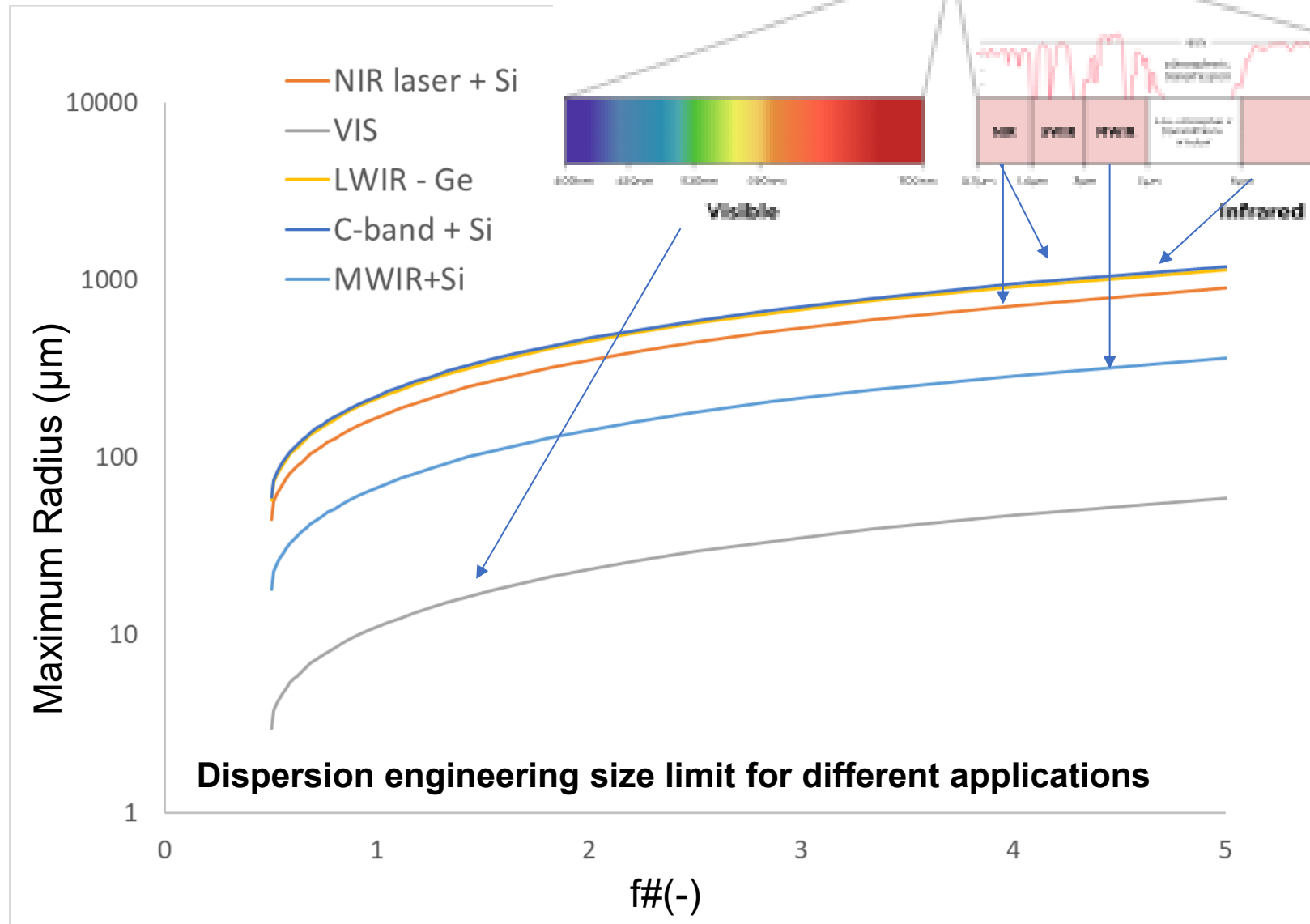
- Materials: index contrast
- Structure: Height + aspect ratio
- Complexity: multi-layers

Literature devices within bounds of theoretical formula*



*F. Presutti and F. Monticone, "Focusing on Bandwidth: Achromatic Metalens Limits," *Optica* **7**, (2020).)

Promising configurations



❖ Ideal target application

- Narrow spectrum
- Small diameters
- High index contrast
- Low NA / high F#

❖ Which platforms have highest potential for dispersion engineered design?

- IR: Si, Ge
- Visible: TiO₂, SiN, GaN
- Height assumed = λ

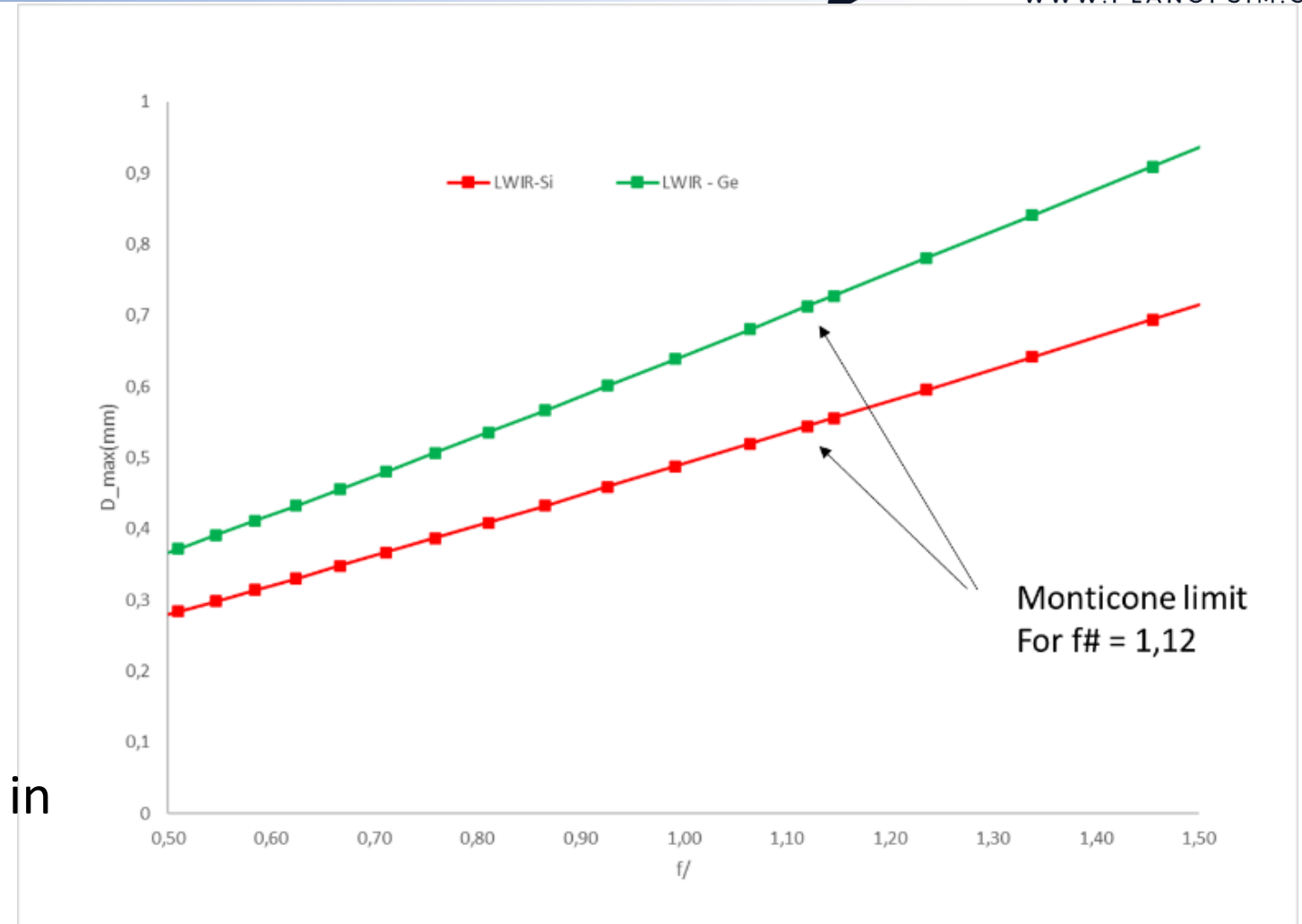
- ❖ Maximum dispersion in dielectric meta-atom

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- ❖ Bandwidth, size and function are connected*

$$R_{max} \leq \frac{\Delta\Phi \cdot c}{\Delta\omega \left(\frac{1}{NA} - \sqrt{\frac{1}{NA^2} - 1} \right)}$$

- ❖ Achromatic flat surfaces have a limit in diameter
 - Only small sizes <1mm can be achieved

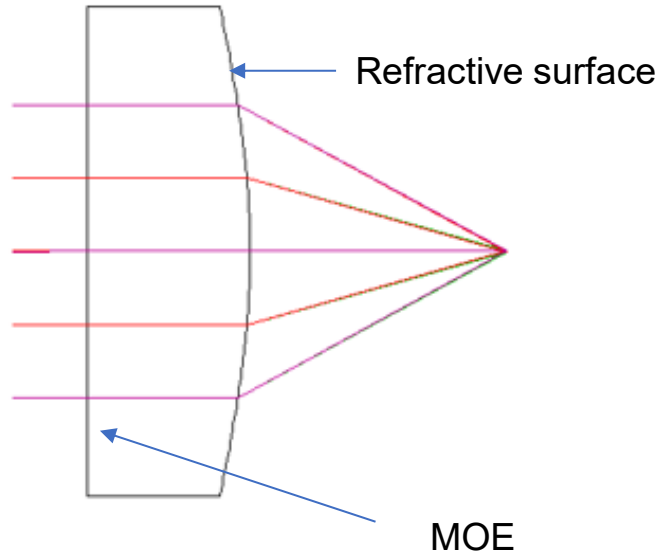


*F. Presutti and F. Monticone, "Focusing on Bandwidth: Achromatic Metalens Limits," Optica **7**, (2020).)

Meta + Refractive hybrids

Example
FOCAL LENGTH = 31.32 NA = 0.5715

12.1



❖ Classical hybrid solution

- Combine meta/diffractive lens with refractive

$$P_t = \frac{1}{f_t} = \frac{1}{f_R} + \frac{1}{f_M}$$

$$\Delta P = P(\lambda_1) - P(\lambda_2) = \frac{n_2 - n_1}{R} + \frac{\lambda_1 - \lambda_2}{f_0 \lambda_0} = 0$$

❖ Achromatic hybrid when

$$f_0 \lambda_0 = -\frac{\Delta \lambda}{\Delta n} R$$

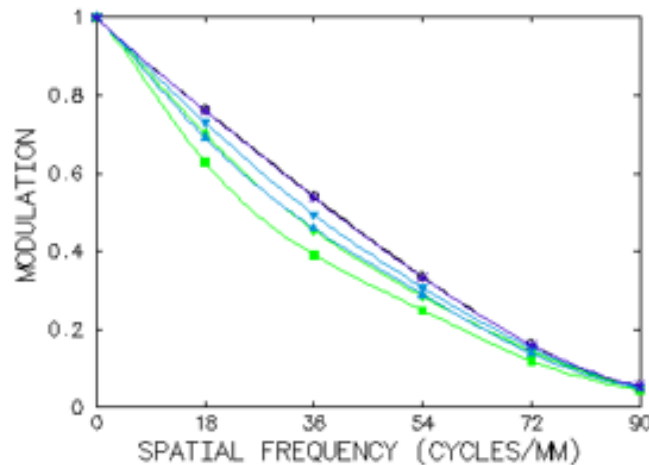
❖ Hybrid design chromatic correction over wide spectrum

- Example LWIR 8-12 um

FIELD POINTS
ON-AXIS T+ Sx
0.07071deg T+ Sx
0.1deg T+ Sx
Ideal

WAVELENGTHS
λ(μm) Weight
1 10 1
2 12 1
3 8 1

Polychromatic MTF of hybrid lens

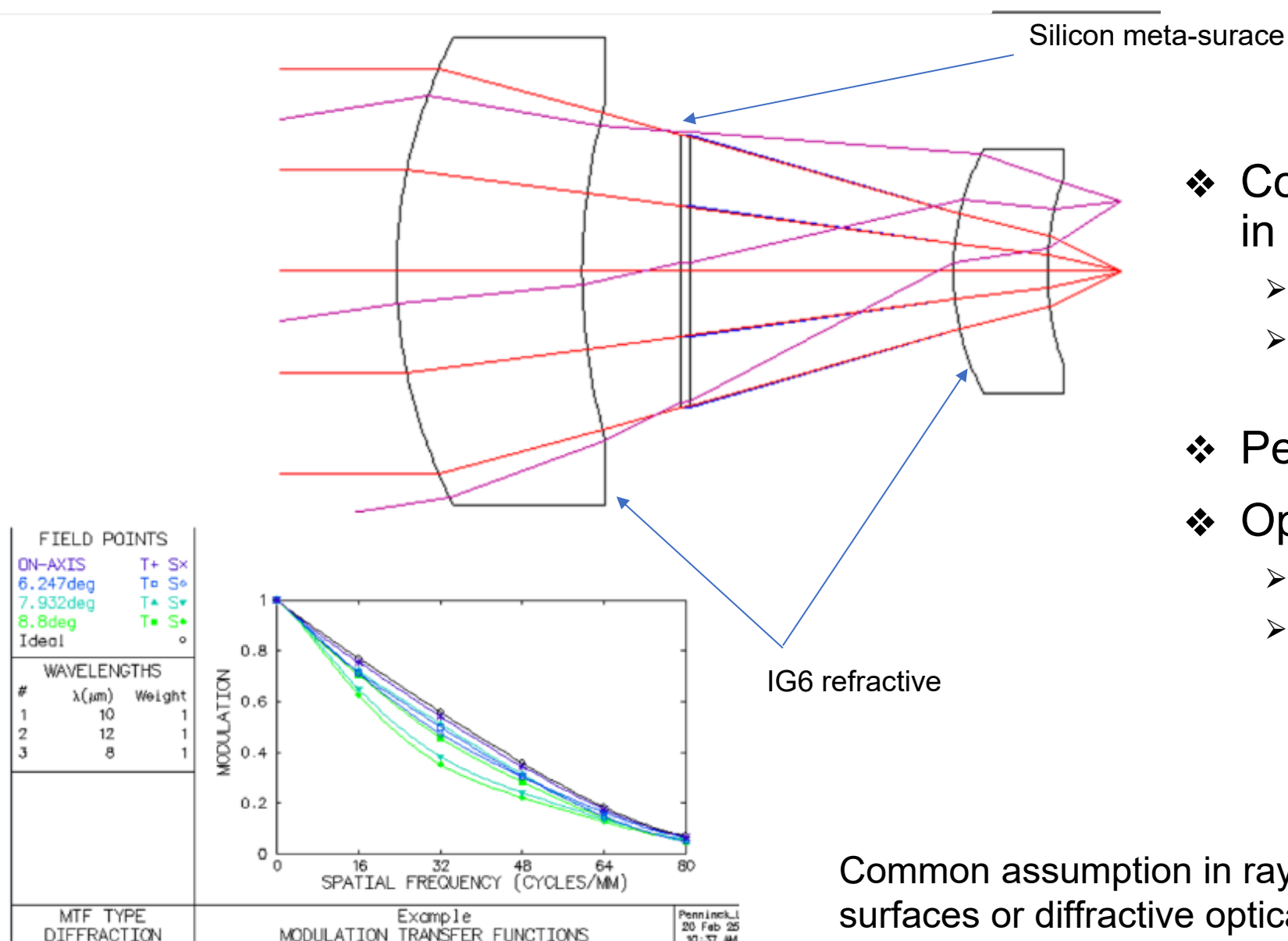


MTF TYPE
DIFFRACTION

Example
MODULATION TRANSFER FUNCTIONS

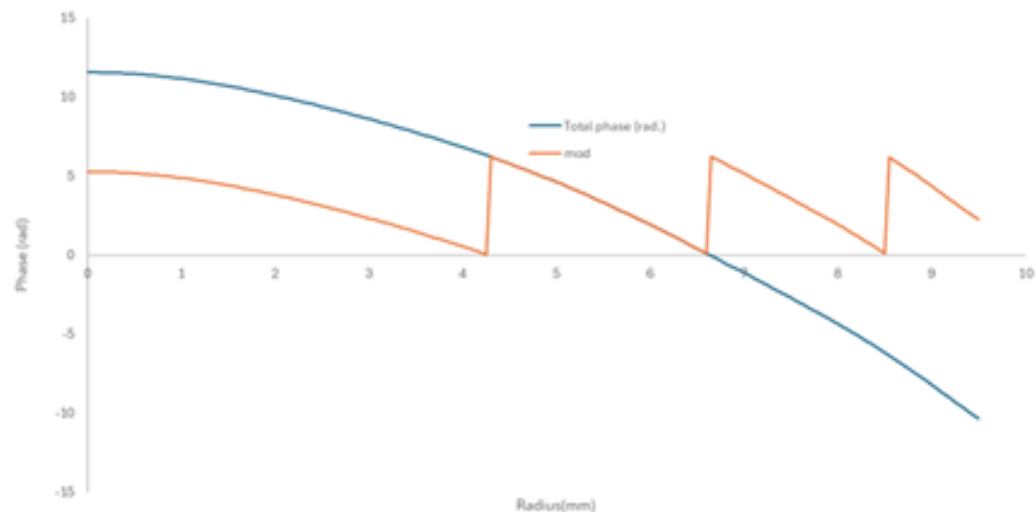
Pennick.L
27 Nov 24
10:00 AM

Example

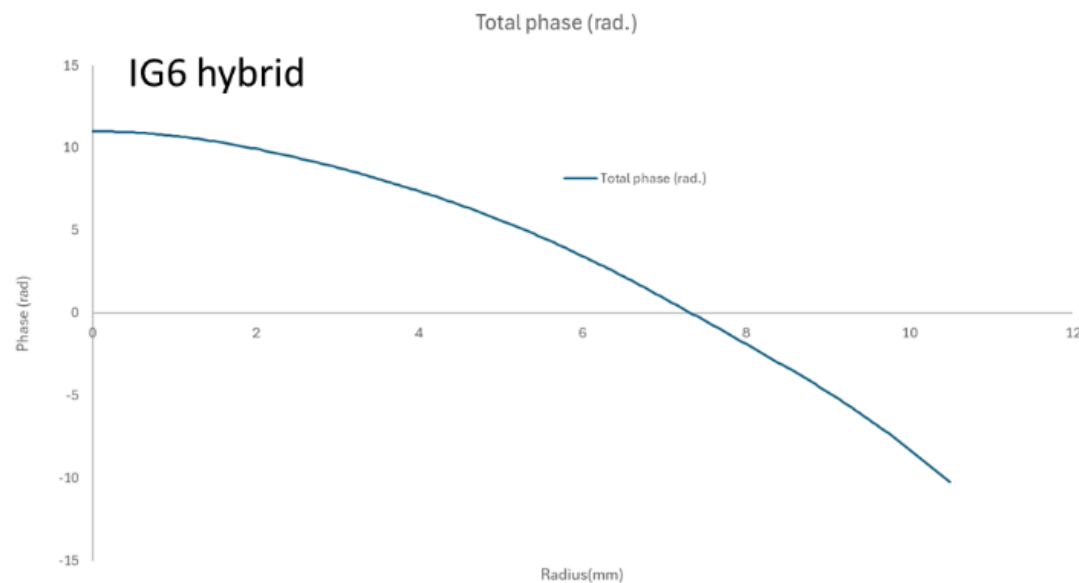
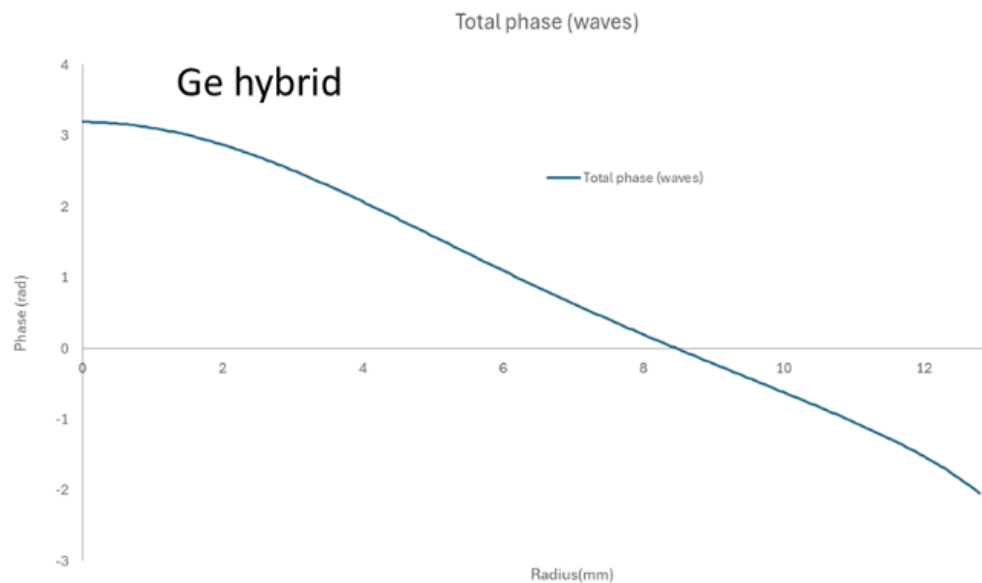


- ❖ Configuration meets specification in multiple iterations
 - Several lens materials
 - Germanium and Silicon metasurface
- ❖ Performance near diffraction limit
- ❖ Optimized via ray tracing
 - Meta-surface as polynomial
 - Constant phase vs. Wavelength

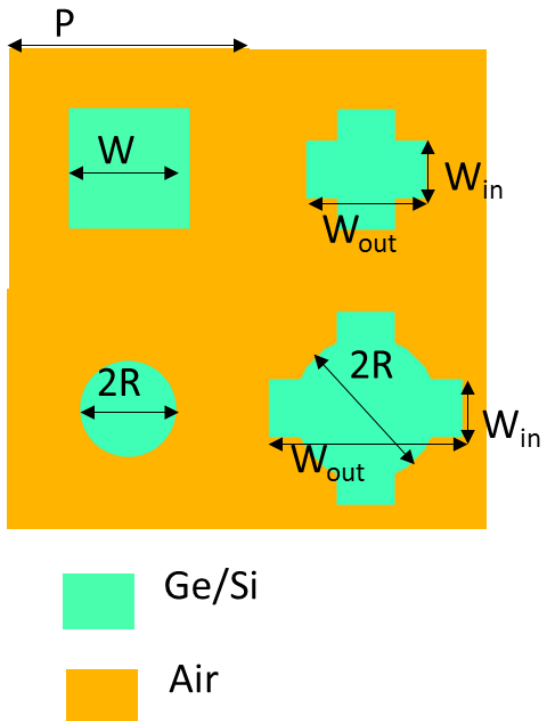
Common assumption in ray tracing but not accurate in meta-surfaces or diffractive optical elements



- ❖ Phase vs. radius for various configurations
- ❖ Meta-surface acts as a corrector with limited optical power



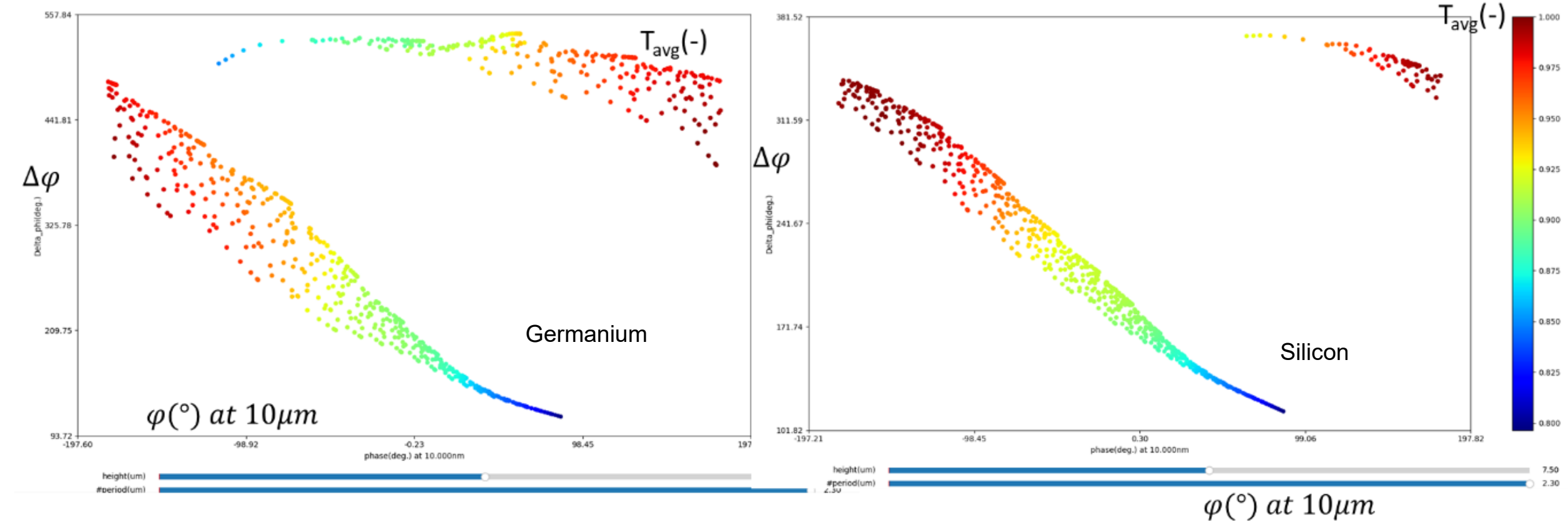
Structures in library



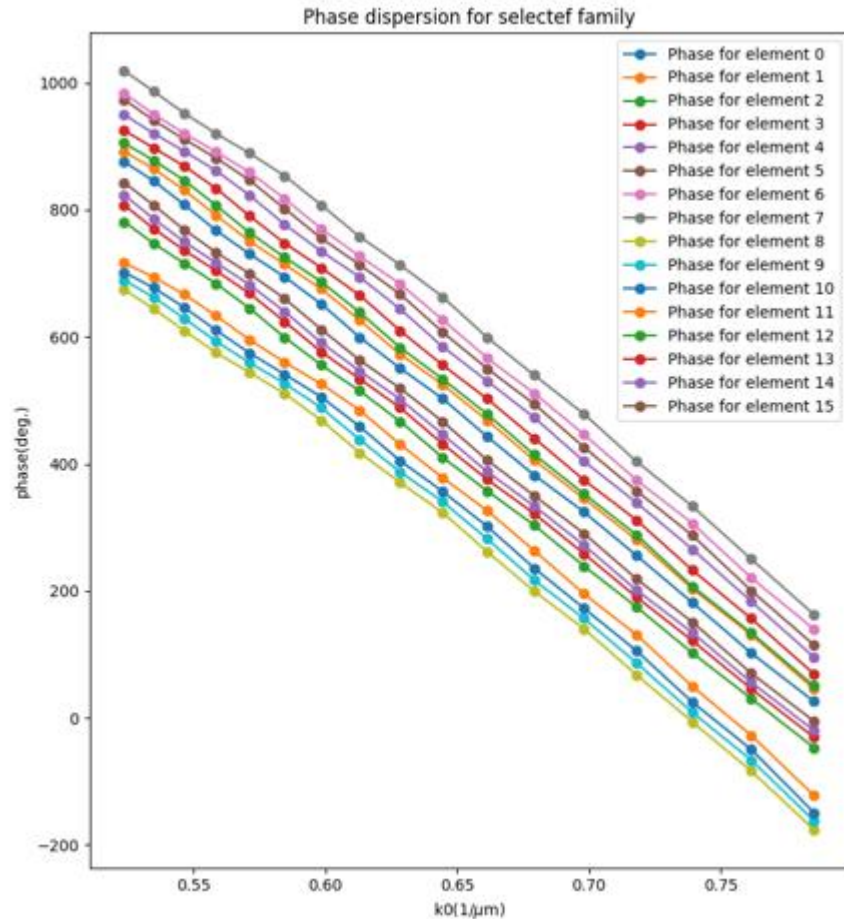
- ❖ Meta-atom shapes for LWIR library
- ❖ Simulation in PlanOpSim Meta-cell (RCWA)
- ❖ Large parameter sweep
 - Several weeks to perform sweep

Parameter	Values
Material	Si +Ge
Unit Cell P	1-3um
Shape parameters	4 shapes
Height	3-12um
Wavelength	8-12um

Sample result



- ❖ Phase and phase dispersion
- ❖ Sample for $H = 10$, $P=2.3\mu\text{m}$
- ❖ Si and Ge produce 0-360° phase coverage
- ❖ Ge library allows phase coverage at constant dispersion



❖ Selected meta-atoms

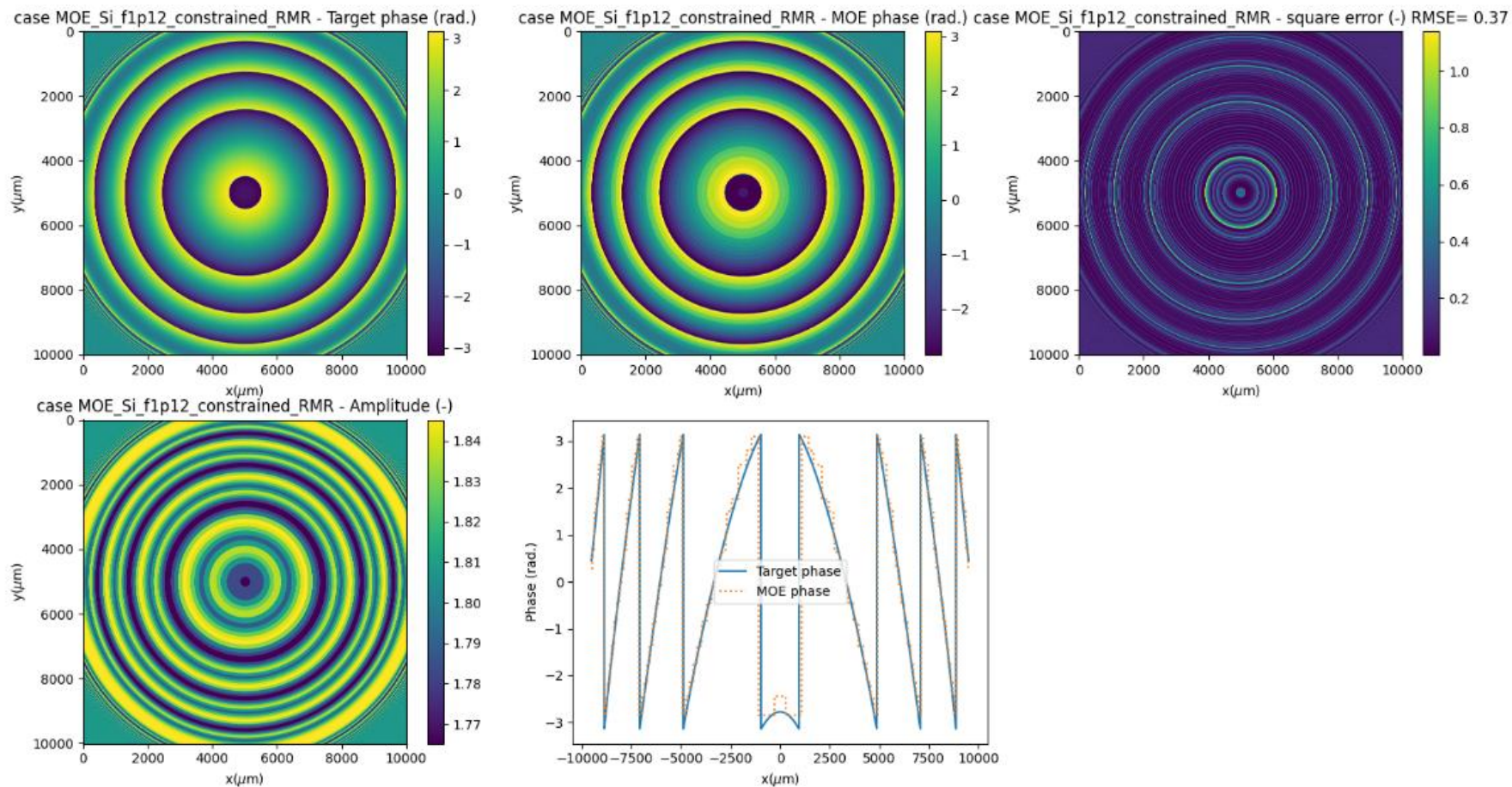
$$\varphi \approx \frac{2\pi}{\lambda} n_{eff} d$$

❖ Wavefront requirement (from ray -tracing)

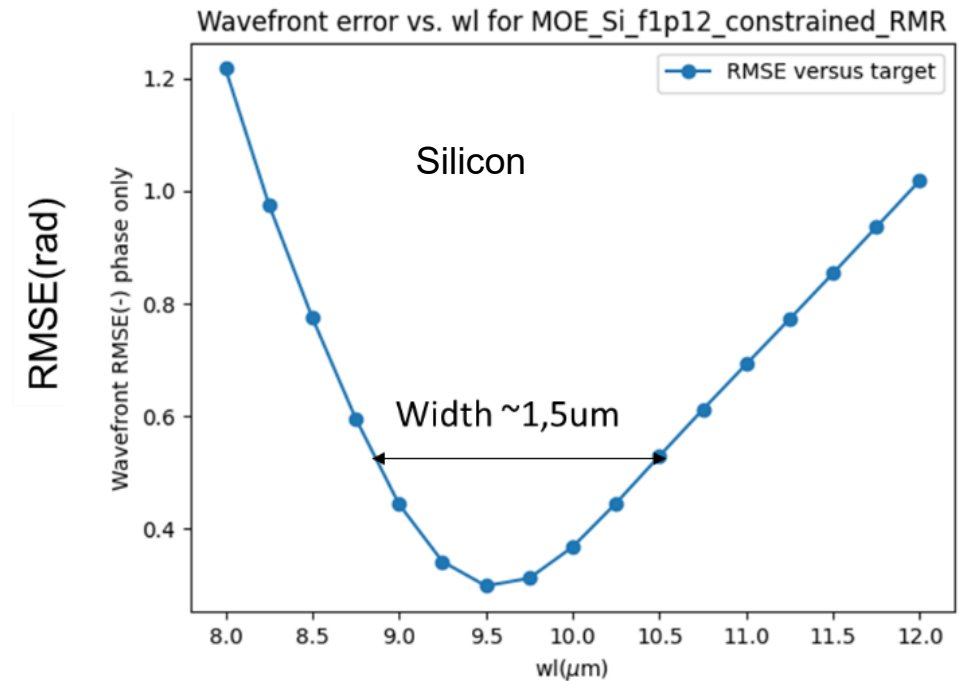
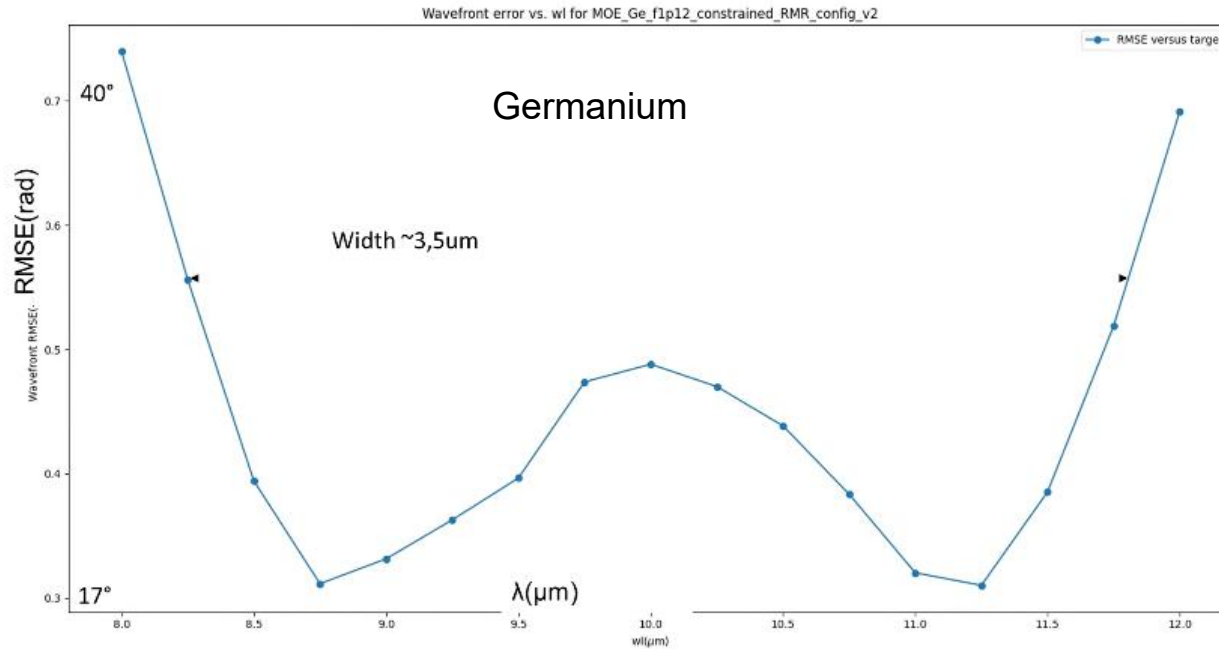
$$\varphi(\lambda) = \sum_n A_n r^{2n} + C(\lambda)$$

Choosing C so that it matches the slope present in our meta-atoms

❖ Similar performance possible with lower n materials if height is increased



- ❖ Meta-atom position matched to waveprofile
- ❖ Least squares match to multi-wavelength profiles



- ❖ Meta-atoms with dispersion control result in a lower error vs. Wavelength
- ❖ Without dispersion control the error rises from the design wavelength towards the edge of the spectrum

How does it compare to DOE?



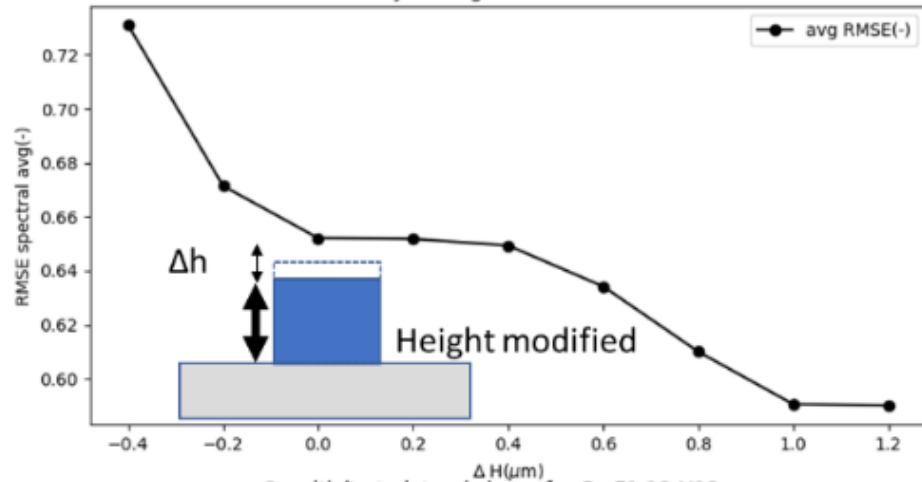
- ❖ Phasefront replication also possible with a Diffractive optical element
- ❖ Comparison of wavefront error over spectrum

Design	Average wavefront error RMSE (-)
Ge	0,66
Si 12 μ m	1,02
DOE (16 level)	0,703

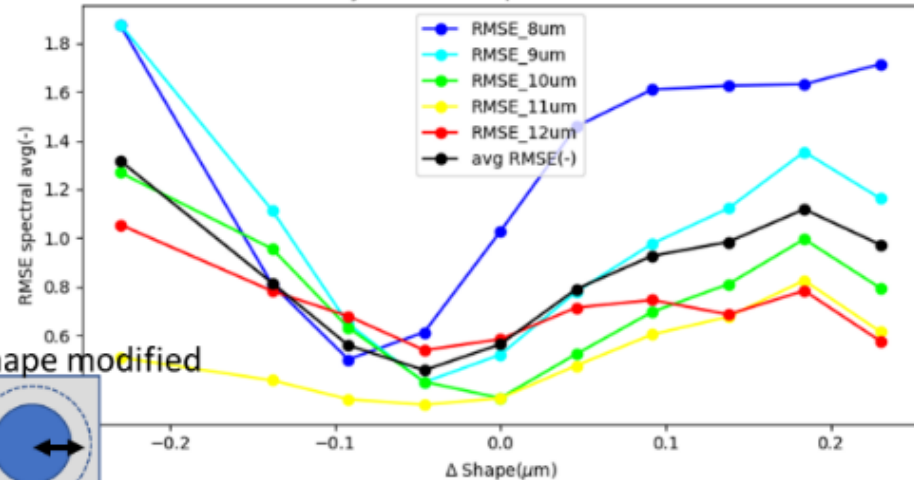
- ❖ Lens system and wavefront re-optimized for each case
- ❖ Dispersion controlled library results in a lower error over spectrum, single wavelength design results in worse average error

Sensitivity analysis

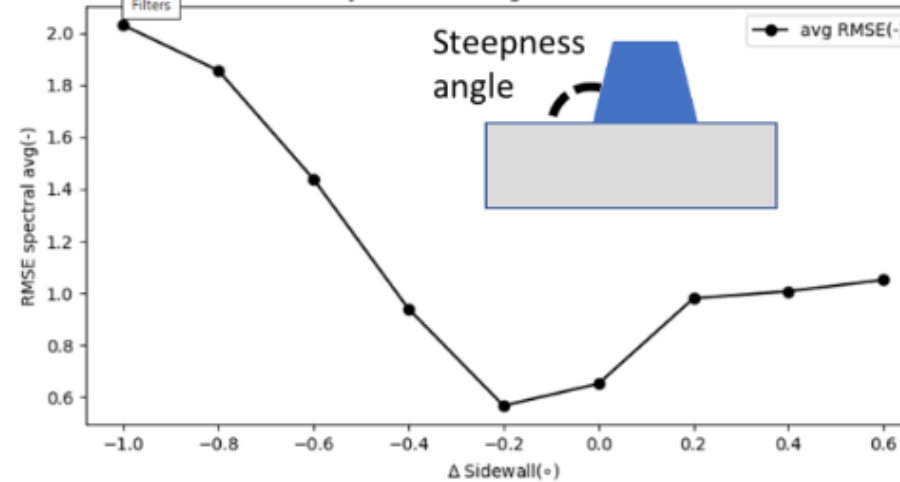
Sensitivity to height for Ge F1.12 H12um



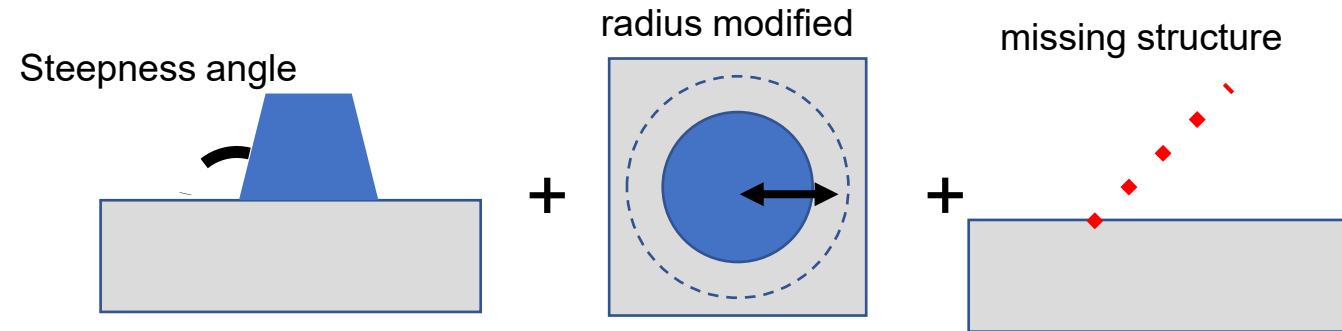
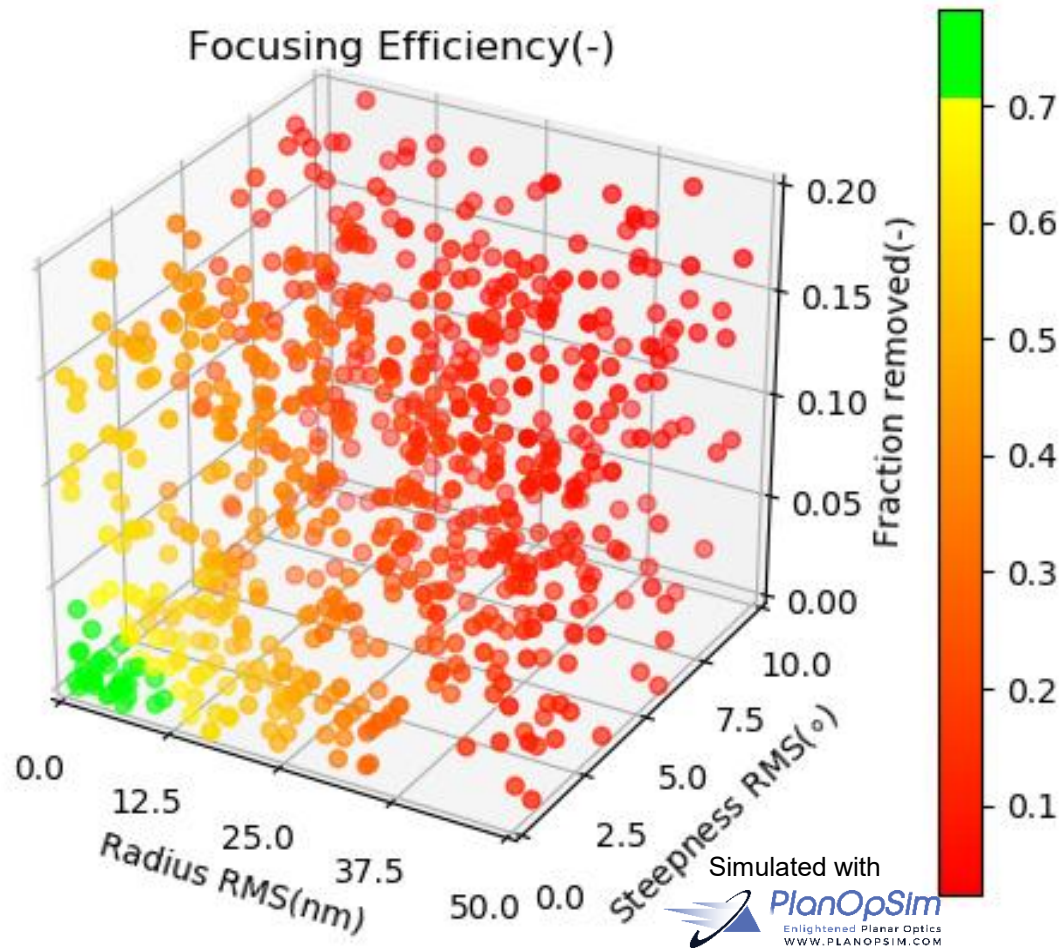
Sensitivity to lateral shape for Ge F1.12 H12um



Sensitivity to sidewall angle for Ge F1.12 H12um



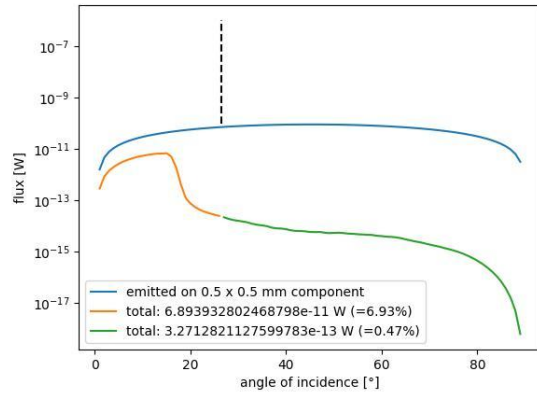
- ❖ Sensitivity analysis versus sidewall, lateral size and height
- ❖ Sidewall angle is the most critical parameter
 - Overetch is worse than underetch



- ❖ Most designs work with nominal structure
- ❖ Effect of manufacturing error
 - Monte Carlo 25'230 metalenses simulated in this plot
 - Systematic errors can be compensated in design
- ❖ Integrate DFM into design process
 - Needs to be integrated into an out-of-the box solution

Preview: multiple meta-surfaces

angular analysis (f: 0.75; wafer 325; a:8; square_pinhole_back: None)

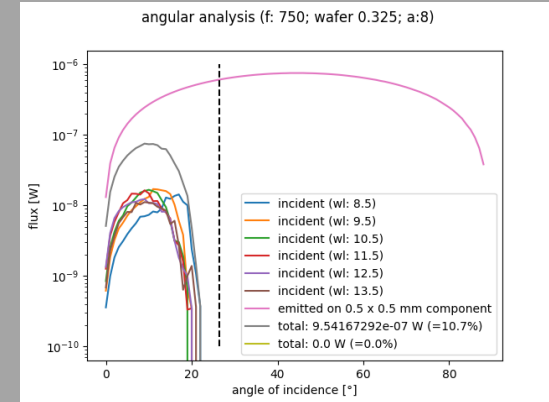


Wave calculation

0,47% stray light / signal

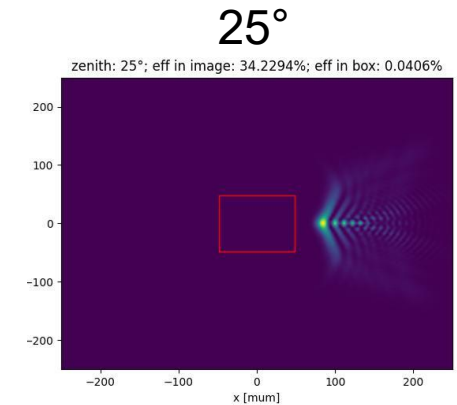
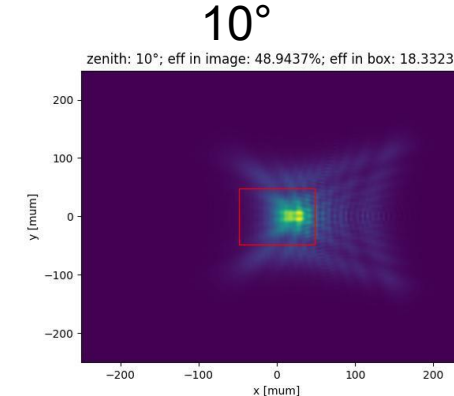
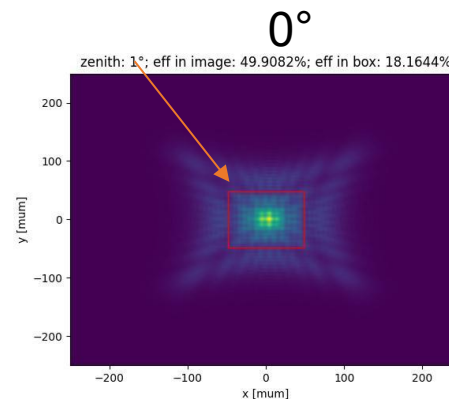
Raytrace calculation

0,0% stray light / signal



- ❖ Diffractive effects are one of the main loss and aberation mechanisms in metasurfaces
- ❖ Impact is application specific
- ❖ Wave based calculation of multiple meta-surface systems
 - Higher order diffraction
 - Aperture diffraction

Plane wave incidence vs. incidence angle

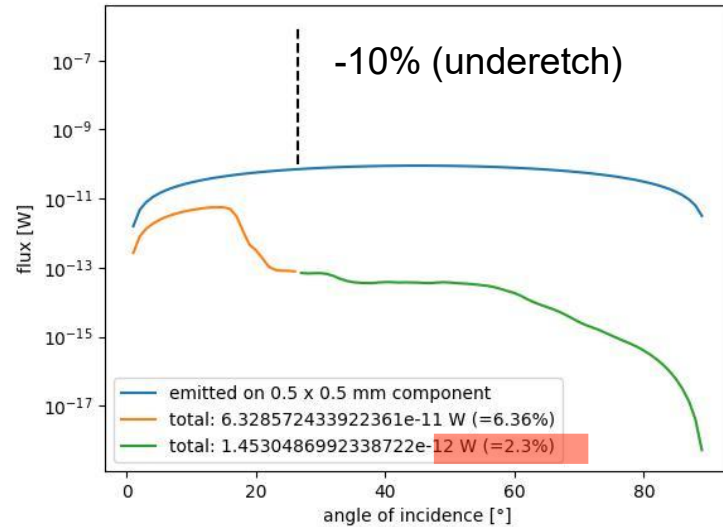


release expected Q2 2026

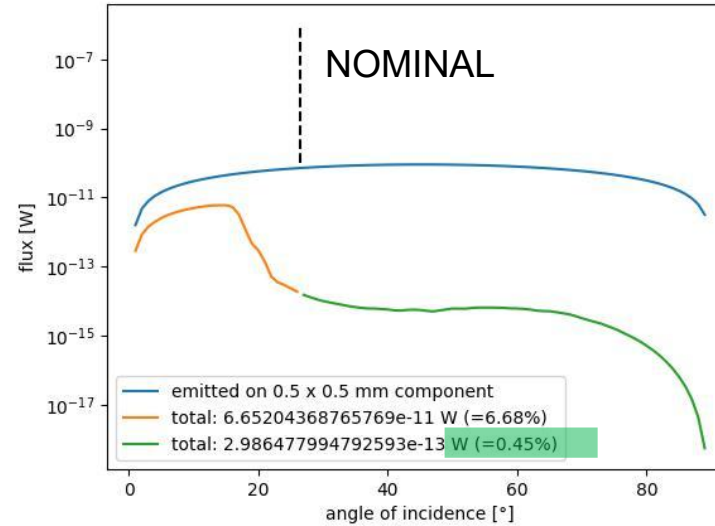
confidential

Preview: system sensitivity

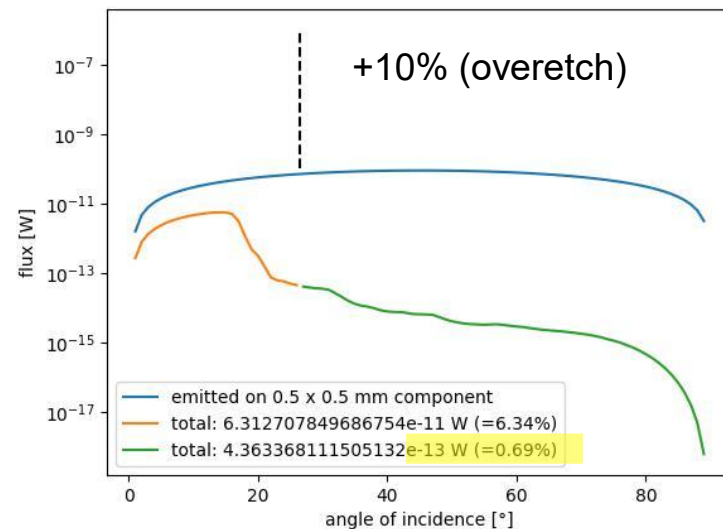
angular analysis (f: 0.9; wafer 325; a:4; square_pinhole_back: None)



angular analysis (f: 0.9; wafer 325; a:4; square_pinhole_back: None)



angular analysis (f: 0.9; wafer 325; a:4; square_pinhole_back: None)



- ❖ Combination: multi-surface + nano-structure tolerancing
- ❖ Guides fabrication process to higher robustness
- ❖ Stray light/signal

Nominal	0.45% (x 1.00)
+10% height	0.69% (x 1.53)
-10% height	2.3% (x 5.11)

- ❖ Hybrid meta-lens system design for LWIR
- ❖ Meta-surfaces for 8-12 μ m range in Silicon and Germanium
- ❖ Wavefront error over spectrum below equivalent DOE design
- ❖ Meta-atoms are most sensitive to sidewall angle in microfabrication

- ❖ Future work: quantifying effect of wavefront error on system performance



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